
**Surface chemical analysis — Auger
electron spectroscopy and X-ray
photoelectron spectroscopy —
Methods used to determine peak
intensities and information required
when reporting results**

*Analyse chimique des surfaces — Spectroscopie des électrons Auger
et spectroscopie de photoélectrons par rayons X — Méthodes utilisées
pour la détermination de l'intensité des pics et informations requises
pour l'expression des résultats*

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Foreword

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This document was prepared by Technical Committee ISO/TC 201, *Surface chemical analysis*, Subcommittee SC 7, *Electron spectroscopies*.

This third edition cancels and replaces the second edition (ISO 20903:2011), which has been technically revised. The main changes compared to the previous edition are as follows:

- subclause 6.3 has been replaced to include modern methods for dealing with co-existing chemical states;
- minor editorial changes have been introduced for clarity.

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